Applicant(s)/Patent Under Application/Control No. Reexamination 09/642,660 SCHNECK ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1643 Christopher H. Yaen **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-Α US-В US-С D US-US-Ε F US-G US-ÚSн US-

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
	N	WO 94/09131			Harris et al		
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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